## Supporting Information

## Carbon formation mechanism of $C_2H_2$ in Ni based catalysts revealed by *in situ* electron microscopy and molecular dynamics simulations

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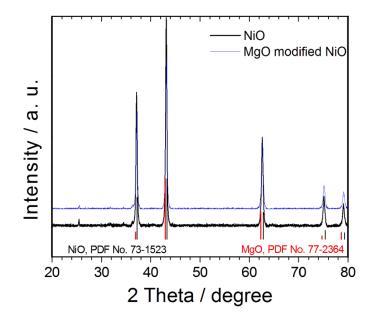
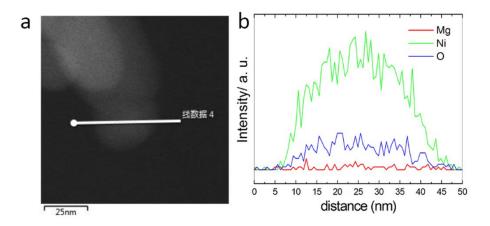
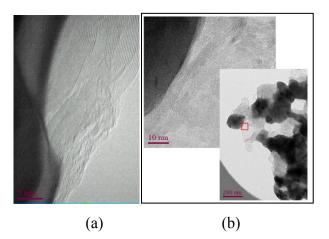


Figure S1. XRD patterns of NiO and MgO modified NiO samples.



**Figure S2.** (a) ADF STEM image of MgO modified NiO particle and (b) The line scanning profiles of elements across the particle in (a).



**Figure S3.** (a) TEM image showing graphitic layers formed in NiO sample at 800°C under  $H_2+C_2H_2$ . Electron energy loss spectrum (EELS) confirms it is carbon. (b) TEM image showing graphic layers formed in MgO modified NiO sample at 800°C under  $H_2+C_2H_2$ . The upper left image is the HRTEM of the region marked by the red square in the low magnification image.